

**Notice of References Cited**

Application/Control No.

10/565,150

Applicant(s)/Patent Under  
Reexamination  
JEDELOO, PIETER WILLEM

Examiner

PING Y. HSIEH

Art Unit

2618

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*		Document Number	Date	Name	Classification
		Country Code-Number-Kind Code	MM-YYYY		
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**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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